

## Module 6: Basics of semiconductor Physics

**Q.1 Define drift current, diffusion current and mobility of charge. (3m)**

**Ans:**

**Drift current** is the electric current that results from the motion of charge carriers (such as electrons or holes) under the influence of an **applied electric field**.

When an electric field is applied across a conducting material (like a semiconductor or conductor), it exerts a force on the free charge carriers, causing them to move in a particular direction. This directed motion of carriers constitutes **drift current**.

The drift current density ( $J_d$ ) can be expressed as:

$$J_d = n \cdot q \cdot \mu \cdot E$$

Where,

$n$  = number of charge carriers per unit volume,

$q$  = charge of a single carrier (e.g., electron charge  $= 1.6 \times 10^{-19}$  C),

$\mu$  = mobility of the charge carriers,

$E$  = applied electric field.

**Diffusion current** is the electric current that arises due to the **concentration gradient** of charge carriers.

If charge carriers (electrons or holes) have a higher concentration in one region than another, they will naturally move from the region of higher concentration to the region of lower concentration. This movement of carriers leads to **diffusion current**.

The diffusion current density ( $J_{diff}$ ) can be expressed as:

$$J_{diff} = -q \cdot D \cdot \nabla n$$

Where,

$q$  = charge of the carrier,

$D$  = diffusion coefficient,

$\nabla n$  = gradient of the carrier concentration ( $n$ ).

The negative sign indicates that the current flows from regions of higher carrier concentration to lower concentrations.

The **mobility** of a charge carrier refers to the ability of a charge carrier to move in response to an applied electric field.

Mobility ( $\mu$ ) is a measure of how quickly a charged particle (electron or hole) moves through a material when exposed to an electric field.

Mobility ( $\mu$ ) is defined as:

$$\mu = V_d / E$$

**where,**

$V_d$  = drift velocity of the carriers,

$E$  = applied electric field.

The unit of mobility is typically expressed in **m<sup>2</sup>/V·s** (square meters per volt-second).

The **conductivity** of a semiconductor refers to its ability to conduct electric current. It is a measure of how easily charge carriers (electrons and holes) can move through the material under the influence of an electric field.

In semiconductors, conductivity depends on the presence of **free charge carriers** (electrons in the conduction band and holes in the valence band), which are influenced by factors such as temperature, doping, and electric fields.

The **electrical conductivity** ( $\sigma$ ) of a semiconductor is given by:

$$\sigma = q (n \mu_n + p \mu_p)$$

**where,**

$q$  = charge of a single electron or hole ( $1.6 \times 10^{-19}$  coulombs),

$n$  = number of electrons in the **conduction band** per unit volume,

$p$  = number of holes in the **valence band** per unit volume,

$\mu_n$  = mobility of electrons,

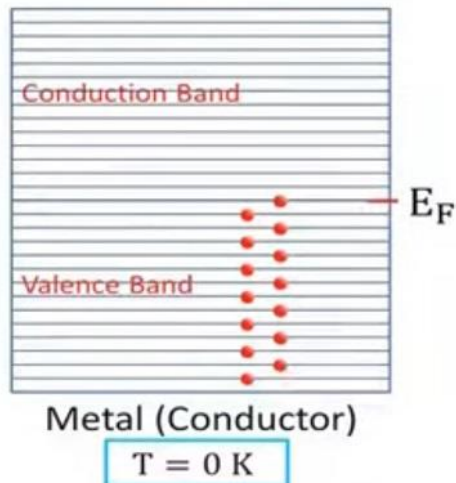
$\mu_p$  = mobility of holes.

For **intrinsic semiconductors**,  $n=p$  (equal number of electrons and holes).

For **extrinsic semiconductors**, the number of electrons or holes can vary depending on the type of doping (n-type or p-type).

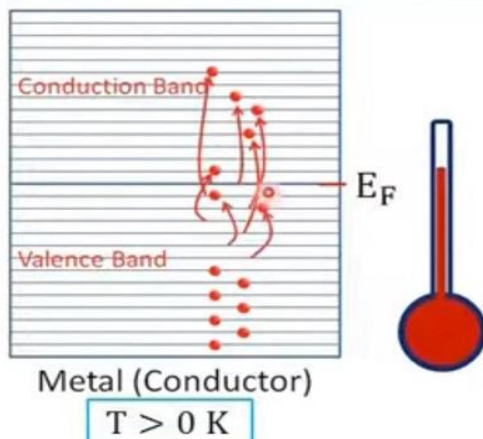
Q.2 What is Fermi level? Write Fermi Dirac distribution function.(3m)

### Fermi Level



- In metal, there is one partially filled band which is a result of conduction band overlapping with valence band.
- In this band lowest energy levels are filled first.
- The highest occupied energy level at absolute zero temperature (0K) is called as Fermi level.
- Energy corresponding to it is called as Fermi energy denoted by  $E_F$

### Fermi Level and Fermi-Dirac Distribution Function



- At temperature  $T > 0K$ , the distribution of electrons over a range of allowed energy levels at thermal equilibrium is given by Fermi-Dirac Distribution function

$$f(E) = \frac{1}{1 + e^{\left(\frac{E - E_F}{kT}\right)}}$$

$f(E)$  is the probability of occupancy for energy level  $E$

$E_F$  is Fermi energy

$T$  is temperature in  $^{\circ}K$  and

$k = 1.38 \times 10^{-23} J/K = 8.625 \times 10^{-5} eV/K$

When  $E < E_F$ :

- The exponent  $(E - E_F)/(k_B T)$  is negative because  $E$  is less than  $E_F$ ,
- $f(E)$  is close to 1, meaning that states below the Fermi level are highly likely to be occupied.

**When  $E > E_F$ :**

- The exponent  $(E - E_F)/(k_B T)$  is positive because  $E$  is greater than  $E_F$ ,
- $f(E)$  is close to 0, meaning that states above the Fermi level are unlikely to be occupied.

**At  $T = 0$  K:**

- $f(E) = 1$  for  $E < E_F$ ,
- $f(E) = 0$  for  $E > E_F$ ,
- The distribution becomes a step function at  $T = 0$  K.

**Q. 3 For intrinsic semiconductor show that the Fermi level lies in the centre of the forbidden energy gap.(3m)**

- It can be shown for intrinsic semiconductors, Fermi energy level  $E_F$  lies midway between conduction and valence band. The proof is given below.
- At any temperature  $T > 0^\circ \text{K}$ ,

$n_c$  = Number of electrons in conduction band

$n_v$  = Number of holes in valence band

$$\text{We have } n_c = N_c e^{-(E_c - E_F) / KT} \quad \dots(6.7.4)$$

Where  $N_c$  = Effective density of states in conduction band

$$\text{And } n_v = N_v e^{-(E_F - E_v) / KT} \quad \dots(6.7.5)$$

Where

$N_v$  = effective density of states in valence band

For best approximation

$$N_c = N_v \quad \dots(6.7.6)$$

For intrinsic semiconductor

$$n_c = n_v$$

$$\therefore N_c e^{-(E_c - E_F) / KT} = N_v e^{-(E_F - E_v) / KT}$$

$$\therefore \frac{e^{-(E_c - E_F) / KT}}{e^{-(E_F - E_v) / KT}} = \frac{N_v}{N_c}$$

$$\therefore e^{-(E_c - E_F - E_F + E_v) / KT} = \frac{N_v}{N_c}$$

$$\therefore e^{-(E_c + E_v - 2E_F) / KT} = \frac{N_v}{N_c}$$

$$\text{as } N_v = N_c = 1$$

$$e^{-(E_c + E_v - 2E_F) / KT} = 1$$

$\therefore$  Taking  $\ln$  on both sides

$$\frac{-(E_c + E_v - 2E_F)}{KT} = 0$$

$$\therefore (E_c + E_v) = 2E_F$$

$$\therefore E_F = \frac{E_c + E_v}{2} \quad \dots(6.7.7)$$



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Thus, the Fermi level in an intrinsic semiconductor lies at the center of forbidden energy gap.

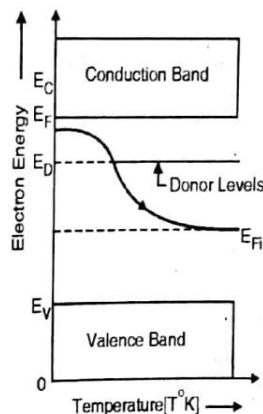
**Q.4 Discuss the effect of variation in temperature on the Fermi energy level of n-type Semiconductor with the help of labelled diagram.(3m)**

(i) **At low temperature :** When the temperature in the semiconductor is low, only few donor atoms get ionized and electrons move from the donor level to the conduction band.

Hence, Fermi level for n-type semiconductor at low temperature lies midway between the bottom of the conduction band and donor level.

(ii) **At moderate temperature :** At moderate temperature all donor atoms are ionized. So, the concentration of electrons in conduction band is equal to the concentration of donor atoms.

When the temperature increases upto moderate value, Fermi level slowly shifts away from the conduction band and moves towards the center of the forbidden gap.



**Fig. 6.8.1: Variation of  $E_F$  with temperature in n-type material**

(iii) **At higher temperature :** At high temperature, the concentration of transfer of electrons from valence band to conduction band is more compared to concentration of electrons from donor atoms and Fermi level is shifted to middle of the forbidden gap.

The variation of Fermi level with temperature for n-type of material is shown in Fig. 6.8.1.

**Q.5 Discuss the effect of variation in temperature on the Fermi energy level of p-type Semiconductor with the help of labelled diagram.(3m)**

(i) **At low temperature** : At low temperature only few acceptor levels are occupied, and simultaneously holes are produced in valence band.

So, Fermi level lies in the middle of the top of the valence band and the acceptor level.

(ii) **At moderate temperature** : At moderate temperature, all acceptor levels are filled.

So, at moderate temperature, Fermi level gradually moves up i.e. moves towards the middle of the forbidden gap.

(iii) **At higher temperature** : At very high temperature, the contribution of conduction band for the formation of holes in the valence band is more compared to acceptor impurity.

Hence, at very higher temperature, Fermi level approaches the middle of the energy gap i.e. the position of  $E_{Fi}$  for intrinsic semiconductor. The variation of  $E_F$  with temperature in p-type material is shown in Fig. 6.8.2.

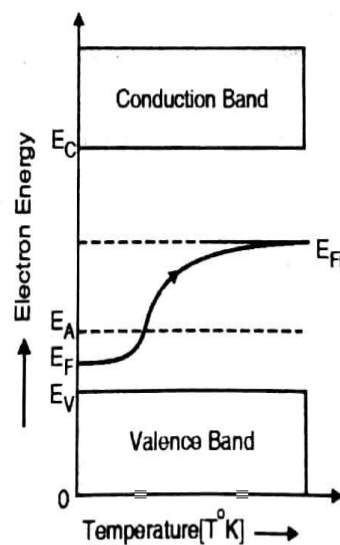


Fig. 6.8.2 : Variation of  $E_F$  with temperature in p-type material

**Q.6 Draw and explain Fermi level diagram of p-n junction diode? (5m)**

Ans: Refer solution of Q.4 and Q.5 for this question.

**Q.7 Draw Fermi level and explain it in detail for conductors.(5m)**



**(a) At  $T = 0^\circ \text{K}$**

- At  $0^\circ \text{K}$  electrons occupy the lower energy levels in the conduction band leaving upper energy levels vacant.
- The band is filled up to a certain energy level  $E_F$ , therefore Fermi level may be regarded as the uppermost filled energy level in conductor at  $0^\circ \text{K}$ . Let us see some important conclusions from Equation (6.6.1).

At  $T = 0^\circ \text{K}$ , levels below  $E_F$  have  $E < E_F$

$$\therefore f(E) = \frac{1}{1 + e^{(E - E_F) / KT}}$$

$$= \frac{1}{1 + e^{-x}}$$

$$= \frac{1}{1 + 0} = 1$$

$f(E) = 1$  means all the levels below  $E_F$  are occupied by electrons.

At  $T = 0^\circ \text{K}$ , levels above  $E_F$  have  $E > E_F$

$$\therefore f(E) = \frac{1}{1 + e^{(E - E_F) / KT}} = \frac{1}{1 + e^{\infty}}$$

$$= \frac{1}{1 + \infty} = 0$$

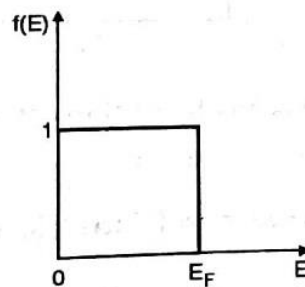
$\therefore f(E) = 0$  means all the levels above  $E_F$  are vacant.

At  $T = 0^\circ \text{K}$ , for  $E = E_F$

$$f(E) = \frac{1}{1 + e^{(E - E_F) / KT}} = \frac{1}{1 + e^0}$$

$\therefore f(E)$  is indeterminable.

This is summarized in Fig. 6.6.2.



**Fig. 6.6.2 : Fermi-Dirac distribution at  $T = 0^\circ \text{K}$**

(b) At  $T > 0^\circ \text{K}$

- At temperature above  $0^\circ \text{K}$ , few electrons are excited to vacant levels above  $E_F$ . This happens to those electrons which are close to  $E_F$  hence probability to find an electron at  $E > E_F$  will become greater than unity which was zero at  $T = 0^\circ \text{K}$ .
- Similarly, due to excitation of electrons, few levels just below  $E_F$  will be become vacant and  $f(E)$  will be slightly reduced which was unity at  $T = 0^\circ \text{K}$ .
- In a simple way one can understand that, what increase in  $f(E)$  at  $T > 0^\circ \text{K}$  above  $E = E_F$  we get is equal to reduction in  $f(E)$  below  $E = E_F$ . This is shown as below in Fig. 6.6.3.

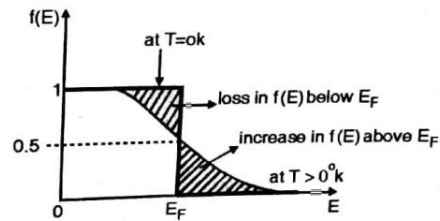


Fig. 6.6.3 : Electron occupancy at  $T > 0^\circ \text{K}$

At  $E = E_F$  for  $T > 0^\circ \text{K}$

$$f(E) = \frac{1}{1 + e^0} = \frac{1}{1 + 1} = \frac{1}{2} = 0.5$$